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(54) Title: AN ELECTRICAL CONTACT AND TESTING PLATFORM

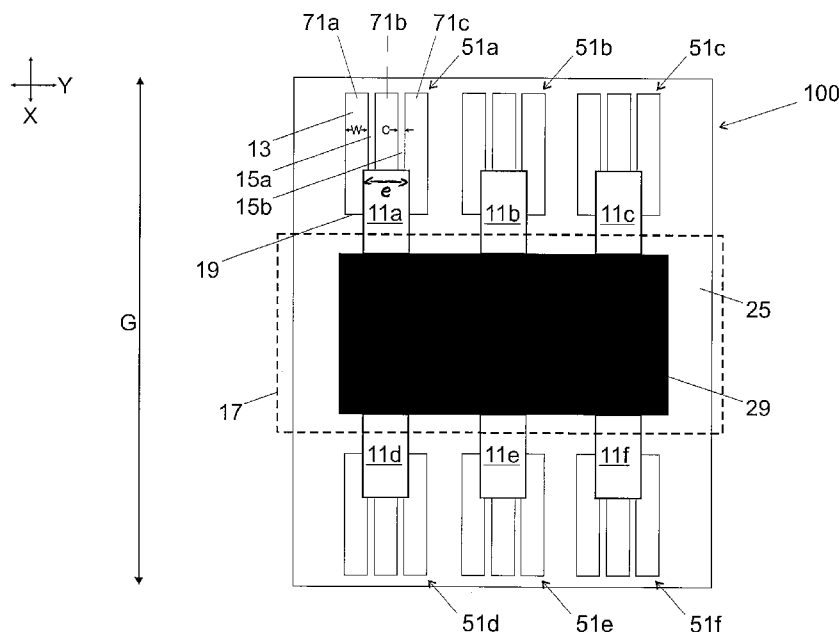


Fig. 3

(57) Abstract: According to the present invention there is provided an electrical contact comprising three or more blades so as to facilitate the establishment of an electrical connection between at least two of the three or more blades by an electrical contact of a component. There is further provided a testing platform suitable for receiving an electrical component to be tested, wherein the testing platform comprising one or more of the aforementioned electrical contacts. There is further provided a test machine component, comprising a holder member which comprises any one of the aforementioned electrical contacts, wherein the test machine component is configured such that it can co-operate with a test machine.

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